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12/426,994	04/21/2009	Jerome Printot	4384-000111	6186

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EXAMINER	
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Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Docket No. 4384-000111US
Action Due Date 12/08/11 Final Date 03/08/12
Action 3 Month Office Action
By MLF Initials FRRM:MN 9/13/11

PTOL-90A (Rev. 04/07)

Although the claims are laden with grammatical and clarity issues, in the interest of compact prosecution, the examiner's broadest reasonable interpretations are provided below in light of the prior art.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

Claims 1-8, 10, and 12-16 are rejected under 35 U.S.C. 102(b) as being anticipated by U.S. Patent No. 6,577,403 ("Primot").

Primot discloses a method for analyzing the wave surface of a light beam in optical control, the method comprising:

(Claim 1) a phase function introduced by a two-dimensional grating substantially positioned in a plane perpendicular to the light beam to be analyzed and optically conjugated of the plane of analysis of the wave surface, which causes a diffraction of the beam into various emerging beams (Col. 5); an intensity function (Col. 5); deformations of an image related to gradients of the analyzed wave surface, such image being formed by the interference of emerging beams and being created and viewed in a plane located at a chosen distance from the grating plane (Col. 3); with the intensity function being uniform on the whole surface of the grating, the step includes the multiplication: of a first phase function, the exclusion function, which defines a meshing of useful zones, which introduces no phase spatial variations in the transmission or the reflection of the light of the analyzed beam, and exclusion zones introducing